PERICOM® SaRonix-ecera PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER

NOMINAL FREQUENCY

32.768 KHz

PRODUCT TYPE

SPEC. NO. (P/N)

CUSTOMER P/N

ISSUE DATE

VERSION

G93270004

TYPE G9 SMD CRYSTAL

Oct.25,2013

В

APPROVED	PREPARED	QA		
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APPROVED BY	AVL Status			
Please return one copy	with approval to PSE-TW			
PSE Technology Corporation				
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Chung Li City, Taoyuan County TEL: 886-3-451-8888	RoHS Compliant			
FAX: 886-3-461-3865	*H	'HF-Halogen Free		
http://www.saronix-ecera.com.tw		*REACH Compliant		

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VERSION HISTORY

Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
Mar.19,2013			Initial Release	
Oct.25,2013			Revised to RoHS Compliant	
	Date Mar.19,2013	Date Date Mar.19,2013	Mar.19,2013	Mar.19,2013 Initial Release



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ELECTRICAL SPECIFICATIONS

SRe Part Number: G93270004

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	90	ΚΩ	Max.
Temperature Coefficient	К	-0.03	ppm/°C ²	Тур.
Operating Temperature Range	TR	-40~85	°C	
Shunt Capacitance	C0	1.3	pF	± 20%
Motional Capacitance	C1	6.4	fF	± 20%
Storage Temperature Range		-55~85	°C	
Aging		± 3	ppm	Max 1st year
Insulation Resistance		500	MΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements		
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	 Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm 		
2	Shear test	A static load of 20N(2.04kgf) using a R0.5 scratch tool, shall be applied on the core of the component and in the direction of the arrow and held for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within $5k\Omega$		
3	Core body strength	A static load of 10N(1.02kgf) using a R0.5 pressure rod shall be applied to the center in the direction of the arrow and held for 10 seconds.			
4	Vibration	Endurance conditioning by a frequency sweep shall be made. The entire frequency range, from 10Hz to 55Hz and return to 10Hz, shall be transversed in 1 minute. Amplitude (total excursion) : 1.5mm, This motion shall be applied for a period of 2 hours in each of 3 mutually perpendicular axes (a total of 6 hours). For other procedures, refer to JIS C 60068-2-6.			
5	Shock	Peak acceleration : 9810m/s2 · Duration of the pulse : 1ms, Three successive shock shall be applied 3 times perpendicular axes. For other procedures, refer to JIS C 60068-2-27.			

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6	Cold	Quartz crystal units shall be stored in the -40 \pm 3 $^{\circ}$ C atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1.				 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat	Quartz crystal units shall be stored in the $100\pm2^{\circ}C$ atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2.				• After conditioning, quartz crystal units to shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	Quartz crystal units shall be stored in the $40\pm2^{\circ}$ C atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.				
9	Change of temperature	cycles of t	ystal units shall temperature cha es conform to JI	ange sho	0	
		1 2 3 4	Temperat -40±3℃ Normal tempe 100±2℃ Normal tempe	rature	Duration 30min. Within 30 sec. 30min. Within 30 sec.	
10	Sealing	Both the test methods specified below shall be applied. Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. Quartz crystal units shall be tested by Mass			 Without repetitive leaking bubbles from quartz crystal units. 1×10-9 Pa · m3/s or less 	
		spectrometric leakage detector to measure the leakage rate of helium gas.				
11	Aging		Quartz crystal units shall be stored in the $85\pm3^{\circ}$ C atmosphere for 720±12 hours.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
					• After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.	
12	Solder-ability	Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds.				Minimum 95% of immersed terminal shall be covered with new uniform solder.
			Items		Conditions	
		1	Solder	Sn-3.	0Ag-0.5Cu	
		2	Flux	Appro metha	oximately 25wt% anol(JIS K 8891) on of resin(JIS K	
			Solder			

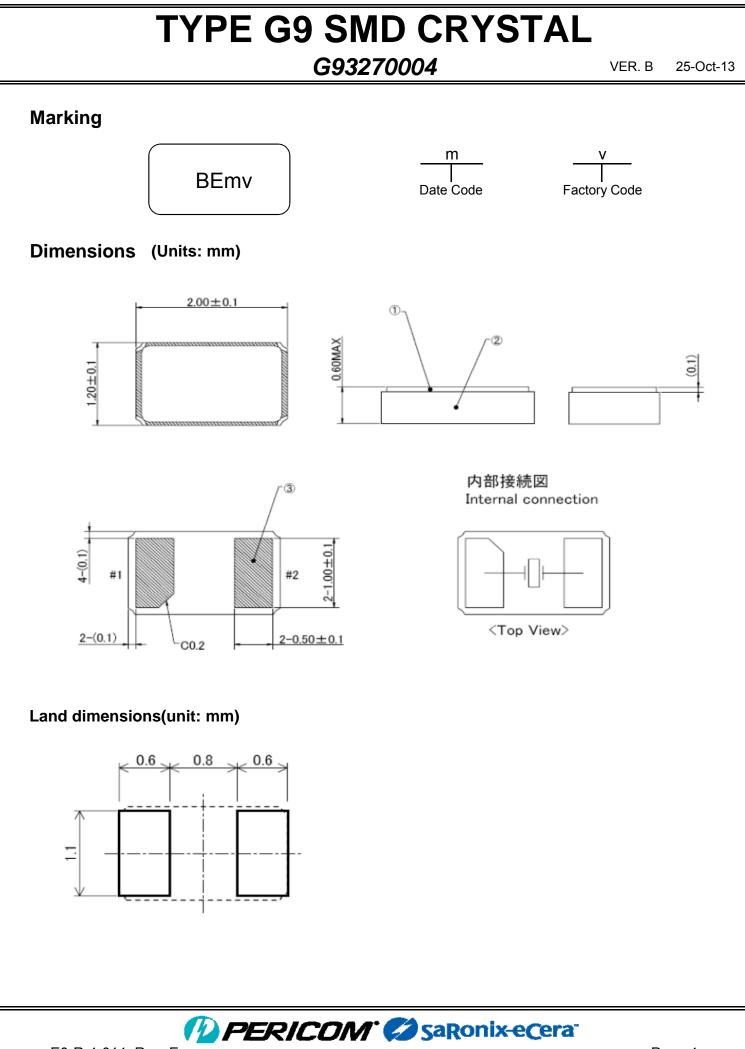


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13	Resistance to	Reflow soldering method
	soldering heat	温度プロファイル
		Temperature profile はんだ付け
		Soldering
		260 - A
		200 の の の の の の の の の の の の の
		型 予熱 現 20 予熱 いた Brochasting Slow cooling(Stored
		Pre-heating 2 D 4 0 2 160 - A construction of the state
		90±10s Within 5s
		• Frequency change: Within ±5ppm
		Peak temperature: 260±5℃ for within 5seconds. Soldering temperature: 220℃ or higher for 60±10
		seconds
		Pre-heating temperature: $160\pm10^{\circ}$ C for 90 ± 10 seconds. Quartz crystal units which is put on PCB shall be the subjected to standard atmospheric conditions for 1 hour, and measured.
		through reflow soldering furnace twice with the condition shown above.
		appearance.
		Soldering iron method • Frequency change: Within ±5ppm
		Terminals shall be applied 400 \pm 10°C soldering iron heat for 3.5 \pm 0.5 seconds twice. • Equivalent series resistance(E.S.R) change: Within 5k Ω
		 After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
		Without distinct deformation in appearance.
14	Solubility to resistance	Soak cleaning• Without mechanical damage such asQuartz crystal units shall be soaked in isopropyl alcoholbreaks and satisfy sealing specification.
		at normal temperature for 90• Frequency change: Within ±5ppmseconds.• Equivalent series resistance(E.S.R)change: Within 5kΩ
		Without distinct deformation in
		appearance.
		Marking shall be legible.

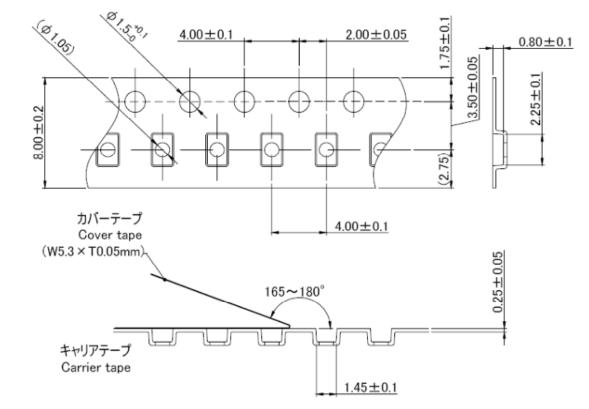
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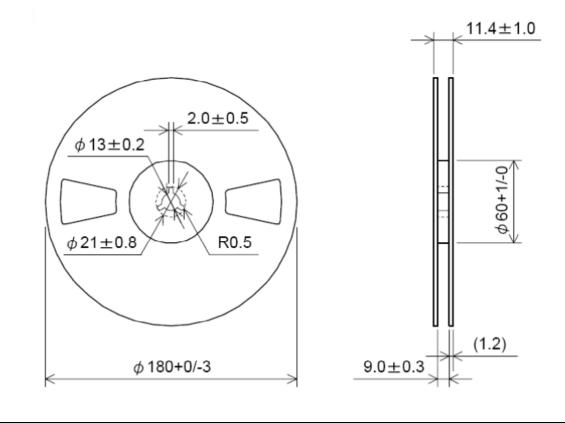
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TAPING



REEL



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